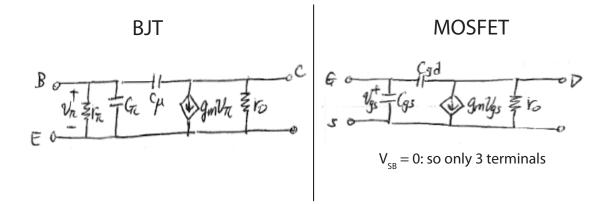
Recitation 21

Recitation 21: Intrinsic Frequency Response of CS & CE Amplifier

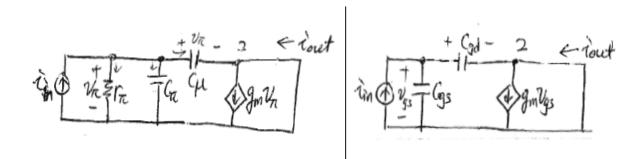
Yesterday, we discussed the intrinsic frequency response of the CE Amplifier. Since there is an analogy between MOSFET & BJT, today we will look at the intrinsic frequency response of a CS Amplifier and compare them.

Small Signal Model



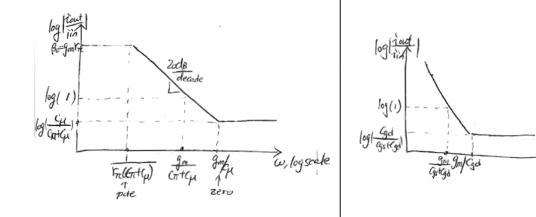
BJT	MOSFET
$\begin{aligned} C_{\pi} &= C_{\rm je} + C_{\rm b} = C_{\rm je} + g_{\rm m} \tau_{\rm F} = C_{\rm je} + g_{\rm m} \left(\frac{w_{\rm B}^2}{2D_{\rm n}}\right) \\ C_{\mu}: \text{depletion capacitance only} \end{aligned}$	$C_{\rm gs} = \frac{2}{3}wLC_{\rm ox} + wC_{\rm ov}$ $C_{\rm gd} = wC_{\rm ov}$

Intrinsic Frequency Response: $R_{\rm s} \rightarrow \infty R_{\rm L} = 0$



BJT	MOSFET
Node 1: $i_{\text{in}} = \frac{v_{\pi}}{\gamma_{\pi}} + jwC_{\pi} \cdot v_{\pi} + jwC_{\mu}v_{\pi}$	Node 1: $i_{\rm in} = jwC_{\rm gs} \cdot V_{\rm gs} + jwC_{\rm gd}V_{\rm gs}$
Node 2: $i_{\text{out}} = g_{\text{m}}v_{\pi} - jwC_{\mu}v_{\pi}$	Node 2: $i_{out} = g_m v_\pi - jw$
$\frac{i_{\text{out}}}{i_{\text{in}}} = \frac{g_{\text{m}}\gamma_{\pi} \left(1 - \frac{jwC_{\mu}}{g_{\text{m}}}\right)}{1 + jw\gamma_{\pi}(C_{\pi} + C_{\mu})}$ $= \frac{\beta_{\text{o}} \left(1 - \frac{jwC_{\mu}}{g_{\text{m}}}\right)}{1 + jw\gamma_{\pi}(C_{\pi} + C_{\mu})}$	$\frac{i_{\rm out}}{i_{\rm in}} = \frac{g_{\rm m} - jwC_{\rm gd}}{jw(C_{\rm gs} + C_{\rm gd})}$

⇒w, log scale



Unit Gain Frequency, $f_{\rm T}$

BJT

 $f_{\rm T} = \frac{1}{2\pi} w_{\rm T} = \frac{1}{2\pi} \frac{g_{\rm m}}{C_{\mu} + C_{\pi}}$ Frequency at which the current gain is reduced to 1(0 dB) This is obtained by:

$$\left|\frac{i_{\text{out}}}{i_{\text{in}}}\right| = \left|\frac{\beta_{\text{o}}\left(1 - \frac{jwC_{\mu}}{g_{\text{m}}}\right)}{1 + jw\gamma_{\pi}(C_{\mu} + C_{\pi})}\right| = 1$$

ignoring the zero on top, $\because \frac{g_{\rm m}}{C_{\mu}} \gg w_{\rm T}$ $\left| \frac{\beta_{\rm o}}{1 + jw\gamma_{\pi}(C_{\mu} + C_{\pi})} \right| = 1$ $\because w_{\rm T} \gg \frac{1}{\gamma_{\pi}(C_{\mu} + C_{\pi})} \therefore w_{\rm T}\gamma_{\pi}(C_{\mu} + C_{\pi}) \gg 1$ $\left| \frac{\beta_{\rm o}}{jw\gamma_{\pi}(C_{\mu} + C_{\pi})} \right| = 1 \implies w_{\rm T} = \frac{g_{\rm m}}{C_{\mu} + C_{\pi}}$

$$f_{\rm T} = \frac{1}{2\pi} \frac{I_{\rm c}/V_{\rm th}}{I_{\rm c}/V_{\rm th} \cdot \tau_{\rm F}} + C_{\rm je} + C_{\mu} \quad (\because g_{\rm m} = \frac{I_{\rm c}}{V_{\rm th}})$$

MOSFET

$$\begin{split} f_{\rm T} &= \frac{1}{2\pi} \frac{g_{\rm m}}{C_{\rm gs} + C_{\rm gd}} \\ (\text{this can be derived similar to the BJT case}) \end{split}$$

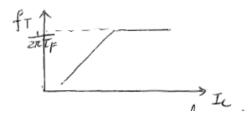
Physical interpretation:

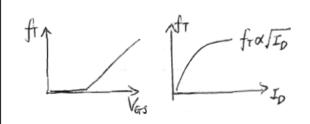
$$f_{\rm T} = \frac{g_{\rm m}}{2\pi (C_{\rm gs} + C_{\rm gd})}$$
$$\approx \frac{1}{2\pi} \frac{g_{\rm m}}{C_{\rm gs}} \approx \frac{1}{2\pi} \frac{w/L\mu_{\rm n}C_{\rm ox}(V_{\rm GS} - 1)}{2/3wLC_{\rm ox}}$$
$$\frac{1}{2\pi} \frac{3}{2} \frac{\mu_{\rm n}(V_{\rm GS} - V_{\rm T})}{L^2} = \frac{3}{2} \frac{\mu_{\rm n}V_{\rm D,SAT}}{L^2} \frac{1}{2\pi}$$
$$\frac{\mu_{\rm n}V_{\rm DSAT}}{L} \sim \text{velocity of carrier}$$

 $\frac{\mu_{\rm n} V_{\rm DSAT}}{L}/L \sim 1/\tau_{\rm T} = \tau_{\rm T} = L/ \, {\rm velocity}$ $\tau_{\rm T}$ is transit time from source to drain

 $f_{\rm T}$ is independent of V.

For high frequency performance, NMOS > PMOS. Scale L as short as possible





At low $I_{\rm c}$, $f_{\rm T}$ is dominated by depletion capacitances at Base-emitter and base collector junctions ($C_{\rm je}$ and C_{μ}). As $I_{\rm c} \uparrow$, diffusion capacitance $g_{\rm m} \tau_{\rm F} \uparrow$, and becomes dominant.

Fundamental limit for frequency response

$$\tau_{\rm F} = \frac{w_{\rm B}^2}{2D_{\rm n,p}}$$

To increase $f_{\rm T}$

- high $I_{\rm c}$ = diffusion cap. limited \implies shrink base width.

- low I_c = depletion cap. limited \implies shrink device area

Another note for MOSFET: the current gain $\rightarrow \infty$ at w = 0. This is because of gate oxide, DC input current = 0.

MOSFET not used as current amplifier at low frequency (input resistance too high) 6.012 Microelectronic Devices and Circuits Spring 2009

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